October 4th - 7th | 2021

PHOTONICS DAYS Berlin Brandenburg

innovation conference

Tektronix

Accelerating Transceiver Characterization and Verification

Presenter: Dr. Ali Emsia





Tektronix High-End Solutions Overview

Tektronix[®]

- Tektronix is a leading T&M company serving engineering and technical professionals
- Founded in 1946, acquired by Danaher in 2007, 2016 a Fortive company
- Headquartered in Beaverton, Oregon
- Leadership positions in key products and markets
- Highly-respected brand based on high quality innovative products, engineering excellence and global service and support
- Award winning:
 - Oscilloscopes
 - Signal Sources
 - Spectrum Analyzers



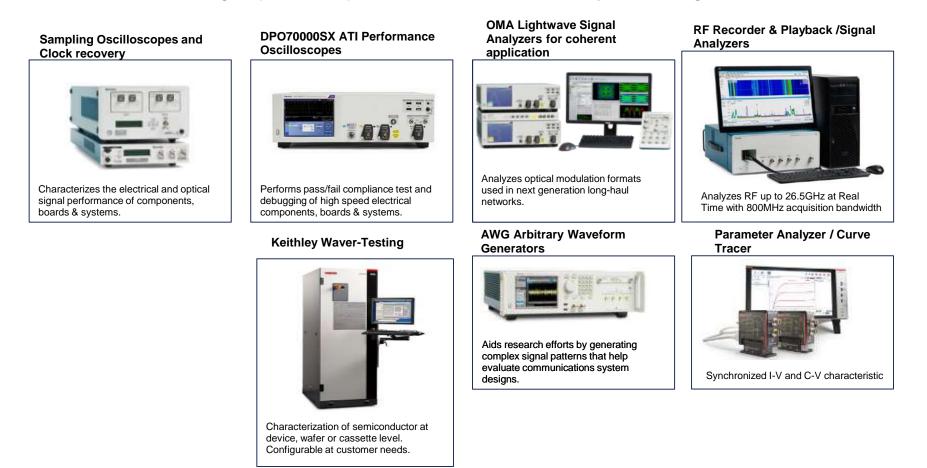
- Keithley is a leader in precision electrical test
- Founded in 1946, acquired by Tektronix in 2010
- Headquartered in Solon, OH
- Offering instruments and systems to meet any measurement requirement from nanovolts to gigahertz
- 21 R&D 100 awards as well as honors from Semiconductor International, Solid State Technology, Electronic Products, Test & Measurement World magazines





Tektronix High-End Solutions Overview

• Tektronix simplifies serial standards testing complexity with measurement expertise and tools that provide accurate test results for high-speed computer and communications system designs

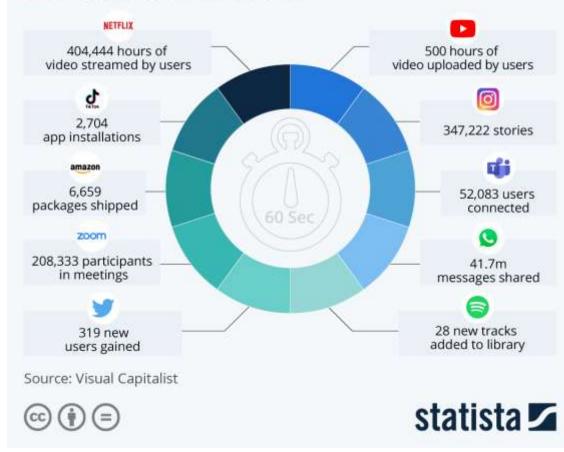




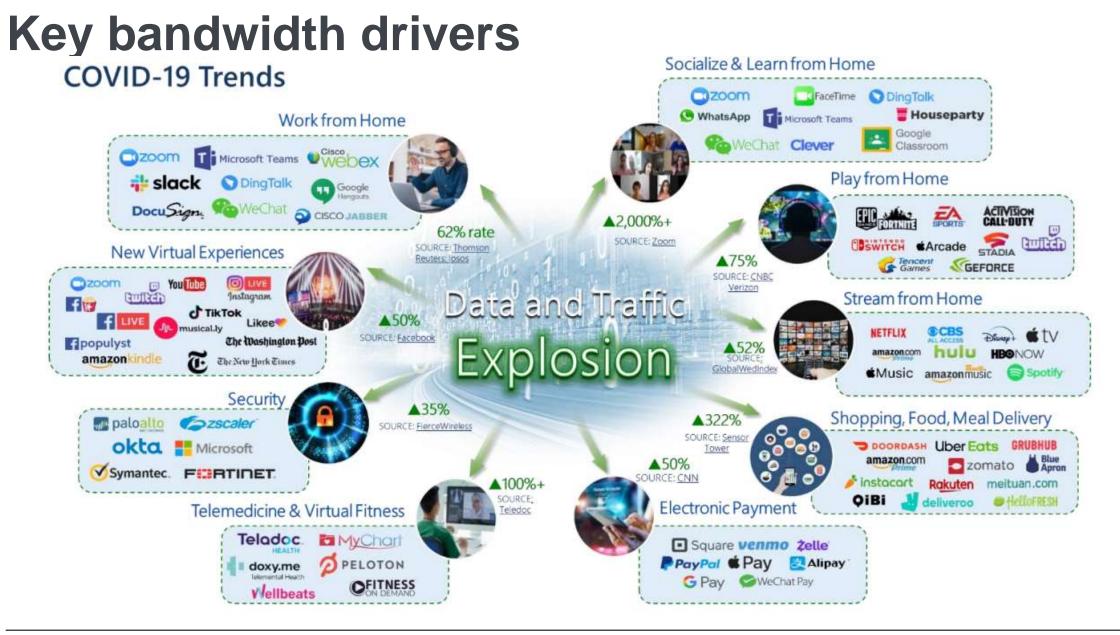
Key bandwidth drivers

A Minute on the Internet in 2020

Estimated amount of data created on the internet in one minute



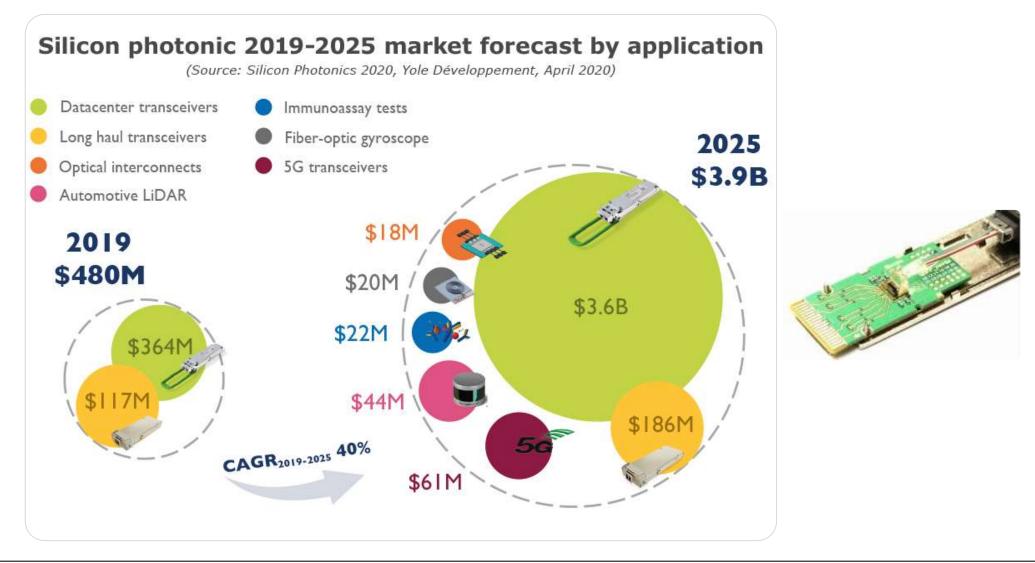








Market Growth





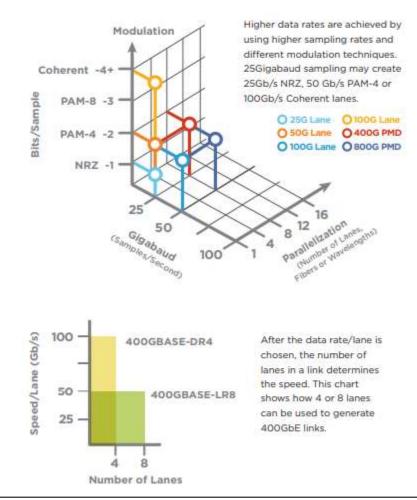


Keeping up with bandwidth demand

How to overcome increasing bandwidth demand

- ✓ More complex modulations
 ✓ NRZ PAM4 QAM
- ✓ More channels
- ✓ Higher baud rates









What's new in Ethernet standards?



			el	ectrical			optical												
			Electrical Interface	Backplane	Twinax Cable	Twisted Pairs	MMF	Parallel SMF	2km SMF	10km SMF	40km SMF								
1983 —		10BASE-				т													
1995 — —		100BASE-				тх	FX			LX									
1998 — —		1000BASE-		КХ	сх	т	SX			LX									
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		5GBASE-		KR		т													
2002 —		10GBASE-	SFI, XFI XSBI, XAUI	KX4, KR	CX4 SFP+DAC	т	SR			LR	ER								
		25GBASE-	25GAUI	KR	CR	т	SR			LR	ER								
2010 —	_	40GBASE-	XLAUI	KR4	CR4	т	SR4		FR	LR4	ER4								
2017		50GBASE-	50GAUI 50GAUI -2	KR, KR2	CR, CR2		SR		FR	LR									
2019		100GBASE-	CAUI10 CAUI4 100GAUI-2	KR4, KR2	CR10, CR4, CR2		SR10 SR4 SR2	PSM4 DR	10X10 CWDM4 CLR4	LR4 10X10	ER4 10X10								
		200GBASE-	200GAUI-4 200GAUI-8	KR4	CR4		SR4	DR4	FR4	LR4									
		400GBASE-	400GAUI-16 400GAUI-8				SR16	DR4	FR8	LR8									
2023 —		800GBASE / 1.6TbE																	





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Pushing the envelope to higher baud rates

Impact on optical transceiver Testing

- Increase in complexity
- Steady uptick in test requirements
- Increase time device spends on the manufacturing floor





Contrast Between PAM-4 and NRZ

- PAM4 Measurements
 - Transmitter and dispersion eye closure quaternary (TDECQ)
- NRZ Measurements
 - Tx Eye Mask

- Outer Optical Modulation Amplitude (OMA_{outer})
- Optical Modulation Amplitude (OMA)

Outer Extinction Ratio (OER)



• Level separation mismatch ratio (RLM)

Contrast Between PAM-4 and NRZ

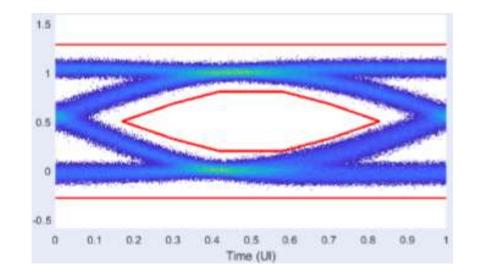
PAM4 TDECQ

 Measures each of the optical transmitter's vertical eye closure as measured through and optical to electrical converter.

$$TDECQ = 10\log_{10}\left(\frac{OMA_{outer}}{6} \times \frac{1}{Q_{t}R}\right)$$

NRZ Eye Mask

 Measures the number of hits on a mask to characterize the BER of a transmitter.



Cost of Test for optical transceivers

	Test station cost [\$k]														
Test Time [min]	150	125	100	75	50										
120															
90															
60															
30															
15															
		C	Cost of test per device	9											



Why is Test time so important?



Go to market faster



Significantly reduce cost of device



Increase throughput / reduce capital expenses



Meet customer demand





Impact of Machine Learning in optical communication

Machine learning has recently seen significant popularity in optical communication with respect to applications such as:

- Optical Performance Monitoring
- Failure and Fault Management

due to its ability to efficiently model systems using abstract inputs.

To cope with high cost and to address reliability concerns, Machine Learning must be explored in this environment to assist testing and provide additional device insight.



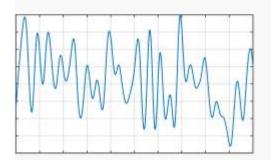


Machine Learning TDECQ

UTILIZING MACHINE LEARNING TO SPEED UP TDECQ MEASUREMENT

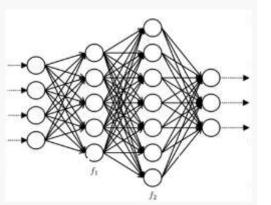
Input:

 Waveform data acquired from scope



Analysis:

 Trained convolutional neural network (CNN)





TDECQ measurement

Output:

TDECQ Computation speed improvement of 20X





TSOVu ™

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